



## **PRODUCT/PROCESS CHANGE NOTIFICATION**

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**PCN IPD-IPC/13/8258**  
**Dated 13 Dec 2013**

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**Voltage Regulator, SOT23 Cu Wire Qualification in Carsem Malaysia**

**Table 1. Change Implementation Schedule**

Forecasted implementation date for change	12-Mar-2014
Forecasted availability date of samples for customer	06-Dec-2013
Forecasted date for <b>STMicroelectronics</b> change Qualification Plan results availability	06-Dec-2013
Estimated date of changed product first shipment	14-Mar-2014

**Table 2. Change Identification**

Product Identification (Product Family/Commercial Product)	see attached list
Type of change	Package assembly material change
Reason for change	will improve service to ST Customers
Description of the change	Progressing on the activities related to quality improvement and along the plan of rationalizing the manufacturing processes, ST is glad to extend the implementation of CU Wire for the SOT23 package in the Carsem subcontractor (Malaysia). For the complete list of the part numbers affected by the change, please refer to the attached Products list. Samples of test vehicles are available right now for immediate customer qualification, while the availability of other samples will be granted upon request.
Change Product Identification	QA number
Manufacturing Location(s)	

## DOCUMENT APPROVAL

Name	Function
Riviera, Antonio	Marketing Manager
Naso, Lorenzo	Product Manager
Spampinato, Sergio Tommas	Q.A. Manager



**PRODUCT/PROCESS  
CHANGE NOTIFICATION**

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***Industrial, Power and Discrete Group***

***Linear Voltage Regulator & Vref BU***

**Voltage Regulator, SOT23 Cu Wire Qualification in Carsem Malaysia.**

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**WHAT:**

Progressing on the activities related to quality improvement and along the plan of rationalizing the manufacturing processes, ST is glad to extend the implementation of CU Wire for the SOT23 package in the Carsem subcontractor (Malaysia).

For the complete list of the part numbers affected by the change, please refer to the attached Products list.

Samples of test vehicles are available right now for immediate customer qualification, while the availability of other samples will be granted upon request.

**WHY:**

This manufacturing change will improve service to ST Customers, standardize processes for the affected package.

**HOW:**

The qualification program mainly consists of reliability tests and comparative electrical characterization.

The related reliability report is annexed to this document.

The changes here reported do not affect the electrical, dimensional and thermal parameters of the products, keeping unchanged all information reported on the relevant datasheets.

**WHEN:**

The implementation **will be finalized** within March 2014

**Marking and traceability:**

Unless otherwise stated by customer specific requirement, the traceability of the parts assembled with the new material set will be ensured by the Q.A. number.

The changes here reported will not affect the electrical, dimensional and thermal parameters keeping unchanged all information reported on the relevant datasheets.

There is as well no change in the packing process or in the standard delivery quantities.

Lack of acknowledgement of the PCN within 30 days will constitute acceptance of the change. After acknowledgement, lack of additional response within the 90 day period will constitute acceptance of the change (Jedec Standard No. 46-C).

In any case, first shipments may start earlier with customer's written agreement.



## Reliability Evaluation Report

SOT23 5L - 1mil Cu wire

Carsem M

UN70-LD3985

General Information		Locations	
Product Line	UN70	Wafer fab	SINGAPORE Ang Mo Kio
Product Description	LD3985 VOUT 2.8V	Assembly plant	CARSEM M
P/N	LD3985M28R	Reliability Lab	Catania Site
Product Group	IPD	Reliability assessment	Pass
Product division	POWER IPD		
Package	SOT 23 5L		
Silicon Process technology	BCD5CS Clean Process		
Production mask set rev.	50769		

### DOCUMENT INFORMATION

Version	Date	Pages	Prepared by	Approved by	Comment
1.0	13-Jun-2013	13	Angelo Donzuso	Giovanni Presti	Final

Note: This report is a summary of the reliability trials performed in good faith by STMicroelectronics in order to evaluate the potential reliability risks during the product life using a set of defined test methods.

This report does not imply for STMicroelectronics expressly or implicitly any contractual obligations other than as set forth in STMicroelectronics general terms and conditions of Sale. This report and its contents shall not be disclosed to a third party without previous written agreement from STMicroelectronics.

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## 1 APPLICABLE AND REFERENCE DOCUMENTS

Document reference	Short description
JESD47E	Stress-Test-Driven Qualification of Integrated Circuits
REL 6043-275.12	UI70-LDK120 in SOT23-5L CU Wire 1 mils SUBCONTRACT Carsem M BCD 6 Technology
REL 6043-146.13	KR33-LD2981 in SOT23 5L 1 mil Cu Wire Carsem M CD BI 20II Technology

## 2 GLOSSARY

DUT	Device Under Test
SS	Sample Size

## 3 RELIABILITY EVALUATION OVERVIEW

### 3.1 Objectives

SOT23 5L - 1mil Cu wire, Carsem M

TV: UN70-LD3985 in SOT23 5L 1 mil Cu wire Carsem M 20 BCD5Cs Clean Process

The qualification plan includes the following TVs:

- UN70-LD3985 in SOT23 5L 1 mil Cu wire Carsem M 20 BCD5Cs Clean Process
- KR33-LD2981 in SOT23-5L 1 mil Cu Wire Qual Carsem M -CD BI 20II Technology
- UI70-LDK120 in SOT23-5L CU Wire 1 mils SUBCONTRACT Carsem M BCD 6 Technology

### 3.2 Conclusion

Qualification Plan requirements have been fulfilled without exception. It is stressed that reliability tests have shown that the devices behave correctly against environmental tests (no failure). Moreover, the stability of electrical parameters during the accelerated tests demonstrates the ruggedness of the products and safe operation, which is consequently expected during their lifetime.

## **4 DEVICE CHARACTERISTICS**

### **4.1 Device description**

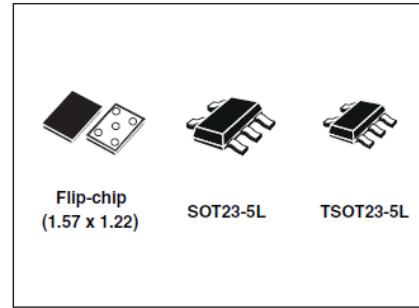


#### **LD3985xx**

Ultra low drop-low noise BiCMOS voltage regulators low ESR capacitors compatible

##### **Features**

- Input voltage from 2.5 V to 6 V
- Stable with low ESR ceramic capacitors
- Ultra low dropout voltage (60 mV typ. at 150 mA load, 0.4 mV typ. at 1 mA load)
- Very low quiescent current (85  $\mu$ A typ. at no load, 170  $\mu$ A typ. at 150 mA load; max 1.5  $\mu$ A in OFF mode)
- Guaranteed output current up to 150 mA
- Wide range of output voltage: 1.22 V; 1.8 V; 2.5 V; 2.6 V; 2.7 V; 2.8 V; 2.9 V; 3 V; 3.3 V; 4.7 V
- Fast turn-on time: typ. 200  $\mu$ s [ $C_O = 1 \mu$ F,  $C_{BYP} = 10 \text{ nF}$  and  $I_O = 1 \text{ mA}$ ]
- Logic-controlled electronic shutdown
- Internal current and thermal limit
- Output low noise voltage 30  $\mu$ V<sub>RMS</sub> over 10 Hz to 100 kHz
- SVR of 60 dB at 1 kHz, 50 dB at 10 kHz
- Temperature range: - 40 °C to 125 °C



to roll off at 10 kHz. High power supply rejection is maintained down to low input voltage levels common to battery operated circuits. Shutdown logic control function is available, this means that when the device is used as local regulator, it is possible to put a part of the board in standby, decreasing the total power consumption. The LD3985xx is designed to work with low ESR ceramic capacitors. Typical applications are in mobile phone and similar battery powered wireless systems.

##### **Description**

The LD3985xx provides up to 150 mA, from 2.5 V to 6 V input voltage. The ultra low drop-voltage, low quiescent current and low noise make it suitable for low power applications and in battery powered systems. Regulator ground current increases only slightly in dropout, further prolonging the battery life. Power supply rejection is better than 60 dB at low frequencies and starts

**Table 1. Device summary**

Part numbers	
LD3985XX122	LD3985XX28
LD3985XX18	LD3985XX29
LD3985XX25	LD3985XX30
LD3985XX26	LD3985XX33
LD3985XX27	LD3985XX47

## **4.2 Construction note**

		<b>P/N LD3985M28R</b>
<b>Wafer/Die fab. information</b>		
Wafer fab manufacturing location	SINGAPORE Ang Mo Kio	
Technology	BCD 5	
Process family	BCD5CS clean process	
Die finishing back side	LAPPED SILICON	
Die size	1330, 960 micron	
Bond pad metallization layers	Metal 1 Ti/AISiCu/TiN 0.450 UM	
Passivation type	USG-PSG-SiON-PIX	
<b>Wafer Testing (EWS) information</b>		
Electrical testing manufacturing location	Ang Mo Kio EWS	
Tester	Die is not tested at EWS	
Test program	NA	
<b>Assembly information</b>		
Assembly site	CARSEM M	
Package description	SOT 23 5L	
Molding compound	CEL8240HF10LXC	
Frame material	SOT23 5L 63 x 48.5 mils Matrix	
Die attach process	Glue	
Die attach material	QMI519	
Die pad size	63 x 48.5mil	
Wire bonding process	Thermosonic	
Wires bonding materials/diameters	1.0mils Cu	
Lead finishing process	pre plated	
Lead finishing/bump solder material	NiPdAu	
<b>Final testing information</b>		
Testing location	CARSEM S	
Tester	ASL1000	
Test program	LDS3985_28.prg	

## **5 TESTS RESULTS SUMMARY**

### **5.1 Test vehicle**

Lot #	Diffusion Lot	Assy Lot	Trace Code	Process/ Package	Product Line	Comments
1	61381JK@1	SGC*ENG23502: M	RVWV*UN70AA6	SOT 23 5L	UN70	

### **5.2 Test plan and results summary**

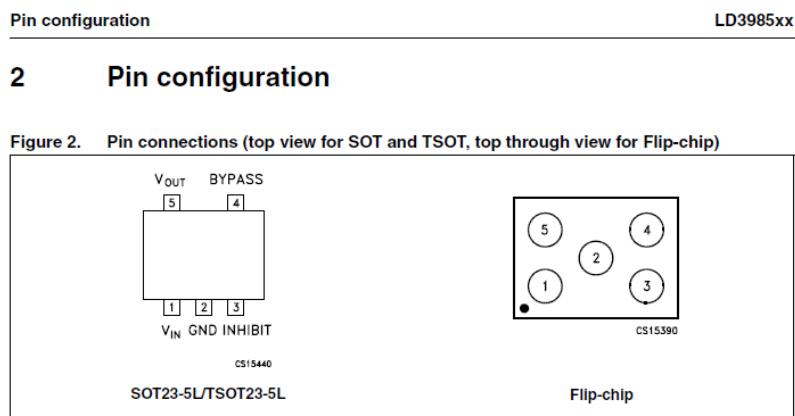
P/N LD3985M28R

Test	PC	Std ref.	Conditions	SS	Steps	Failure/SS		Note
						Lot 1		
<b>Die Oriented Tests</b>								
HTSL	N	JESD22 A-103	Ta = 150°C			168 H	0/25	
						500 H	0/25	
						1000 H	0/25	
HTSL	N	JESD22 A-103	Ta = 175°C			168 H	0/25	Engineering evaluation
						500 H	0/25	
						1000 H	0/25	
<b>Package Oriented Tests</b>								
PC		JESD22 A-113	Drying 24 H @ 125°C Store 168 H @ Ta=85°C Rh=85% Oven Reflow @ Tpeak=260°C 3 times		Final	Pass		
AC	Y	JESD22 A-102	Pa=2Atm / Ta=121°C		168 H	0/25		
TC	Y	JESD22 A-104	Ta = -65°C to 150°C		100 cy	0/25		
					200 cy	0/25		
					500 cy	0/25		
THB	Y	JESD22 A-101	Ta = 85°C, RH = 85%, 5V		168 H	0/25		
					500 H	0/25		
					1000 H	0/25		
<b>Other Tests</b>								
ESD	N	AEC Q101-001, 002 and 005	HBM CDM		1KV, 1,5KV, 2KV	9	Pass	
					100V 200V 500V	9	Pass	

## **6 ANNEXES**

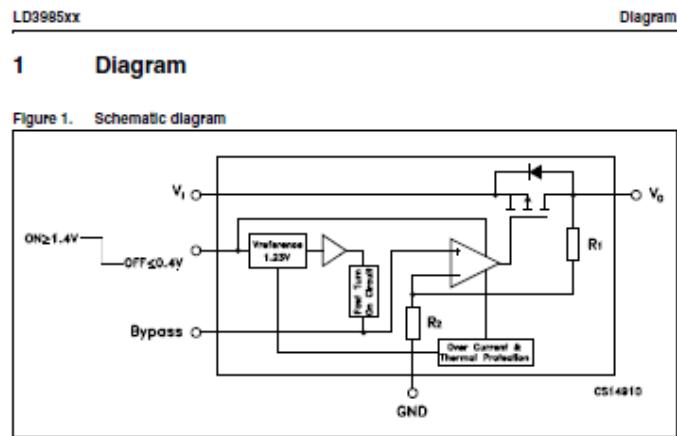
### **6.1 Device details**

#### **6.1.1 Pin connection**


**Table 2. Pin description**

Pin n° for SOT23-5L/ TSOT23-5L	Pin n° for Flip-chip	Symbol	Name and function
1	4	$V_I$	Input voltage of the LDO
2	2	GND	Common ground
3	1	$V_{INH}$	Inhibit input voltage: ON MODE when $V_{INH} \geq 1.2$ V, OFF MODE when $V_{INH} \leq 0.4$ V (Do not leave floating, not internally pulled down/up)
4	5	BYPASS	Bypass pin: connect an external capacitor (usually 10 nF) to minimize noise voltage
5	3	$V_O$	Output voltage of the LDO

### 6.1.2 Block diagram



### 6.1.3 Bonding diagram

DOCUMENT 8404455

REVISION A

CONTROLLED DOCUMENT (Check latest revision)

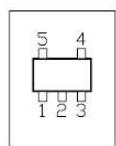
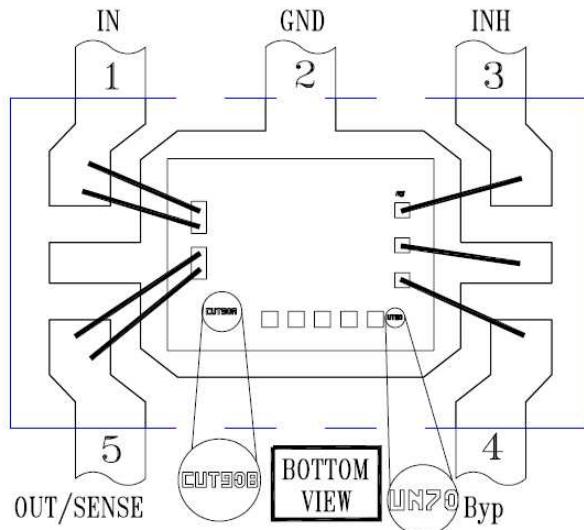
DATE 05-JUL-2012

page: 1/1

**TITLE : CARSEM M - MBD for RVWV\*UN70AA6**

FRAME PAD :  $63 \times 48.5$  mils  
1,6 x 1,23 mm

MAX DIE SIZE:  $57 \times 42.5$  mils  
1,44 x 1,07 mm

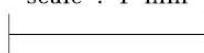


5L MATRIX SOT23 HD  
(opt # 01B)

(DIE DOWN CONFIG)

PINOUT AFTER FORMING "DIE DOWN"

scale : 1 mm



E.S.D. PROGRAM IS MANDATORY

### 6.1.4 Package outline/Mechanical data

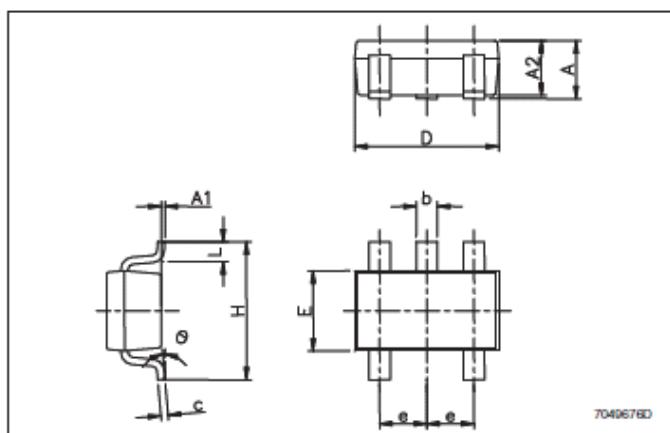
LD3985xx

Package mechanical data

## 7 Package mechanical data

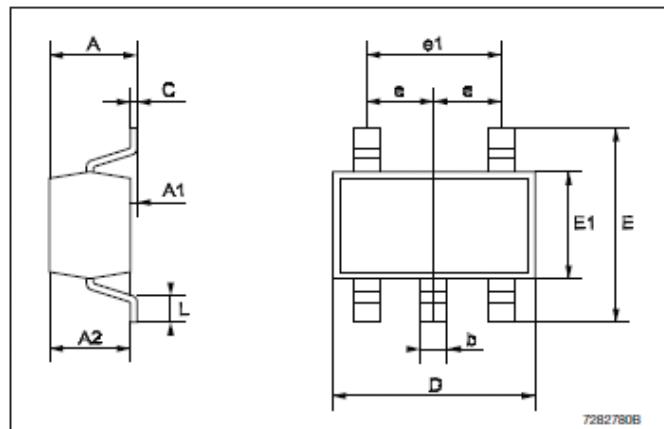
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
 ECOPACK® is an ST trademark.

SOT23-5L mechanical data						
Dim.	mm.			mils.		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	0.90		1.45	35.4		57.1
A1	0.00		0.10	0.0		3.9
A2	0.90		1.30	35.4		51.2
b	0.35		0.50	13.7		19.7
C	0.09		0.20	3.5		7.8
D	2.80		3.00	110.2		118.1
E	1.50		1.75	59.0		68.8
g		0.95			37.4	
H	2.60		3.00	102.3		118.1
L	0.10		0.60	3.9		23.6



**LD3985xx**
**Package mechanical data**
**TSOT23-5L mechanical data**

Dim.	mm.			mils.		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A			1.1			43.3
A1	0		0.1			3.9
A2	0.7		1.0	27.6		39.4
b	0.3		0.5	11.8		19.7
C	0.08		0.2	3.1		7.9
D		2.9			114.2	
E		2.8			110.2	
E1		1.6			63.0	
e		0.95			37.4	
e1		1.9			74.8	
L	0.3		0.6	11.8		23.6



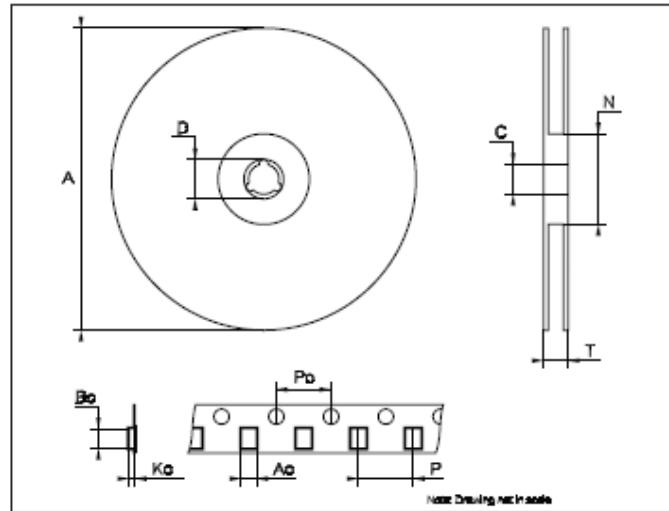
Doc ID 9587 Rev 14

15/23

## Package mechanical data LD3985xx

## Tape &amp; reel SOT23-xL mechanical data

Dim.	mm.			Inch.		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A			180			7.086
C	12.8	13.0	13.2	0.504	0.512	0.519
D	20.2			0.795		
N	60			2.362		
T			14.4			0.567
Ao	3.13	3.23	3.33	0.123	0.127	0.131
Bo	3.07	3.17	3.27	0.120	0.124	0.128
Ko	1.27	1.37	1.47	0.050	0.054	0.058
Po	3.9	4.0	4.1	0.153	0.157	0.161
P	3.9	4.0	4.1	0.153	0.157	0.161



## 6.2 Test Description

Test name	Description	Purpose
<b>Die Oriented</b>		
<b>HTSL</b> High Temperature Storage Life	The device is stored in unbiased condition at the max. temperature allowed by the package materials, sometimes higher than the max. operative temperature.	To investigate the failure mechanisms activated by high temperature, typically wire-bonds solder joint ageing, data retention faults, metal stress-voiding.
<b>Package Oriented</b>		
<b>PC</b> Preconditioning	The device is submitted to a typical temperature profile used for surface mounting devices, after a controlled moisture absorption.	As stand-alone test: to investigate the moisture sensitivity level. As preconditioning before other reliability tests: to verify that the surface mounting stress does not impact on the subsequent reliability performance. The typical failure modes are "pop corn" effect and delamination.
<b>AC</b> Auto Clave (Pressure Pot)	The device is stored in saturated steam, at fixed and controlled conditions of pressure and temperature.	To investigate corrosion phenomena affecting die or package materials, related to chemical contamination and package hermeticity.
<b>TC</b> Temperature Cycling	The device is submitted to cycled temperature excursions, between a hot and a cold chamber in air atmosphere.	To investigate failure modes related to the thermo-mechanical stress induced by the different thermal expansion of the materials interacting in the die-package system. Typical failure modes are linked to metal displacement, dielectric cracking, molding compound delamination, wire-bonds failure, die-attach layer degradation.
<b>THB</b> Temperature Humidity Bias	The device is biased in static configuration minimizing its internal power dissipation, and stored at controlled conditions of ambient temperature and relative humidity.	To evaluate the package moisture resistance with electrical field applied, both electrolytic and galvanic corrosion are put in evidence.
<b>Other</b>		
<b>ESD</b> Electro Static Discharge	The device is submitted to a high voltage peak on all his pins simulating ESD stress according to different simulation models. CBM: Charged Device Model HBM: Human Body Model MM: Machine Model	To classify the device according to his susceptibility to damage or degradation by exposure to electrostatic discharge.
<b>LU</b> Latch-Up	The device is submitted to a direct current forced/sunk into the input/output pins. Removing the direct current no change in the supply current must be observed.	To verify the presence of bulk parasitic effect inducing latch-up.



## Public Products List

PCN Title : Voltage Regulator, SOT23 Cu Wire Qualification in Carsem Malaysia

PCN Reference : IPD-IPC/13/8258

PCN Created on : 09-DEC-2013

Subject : Public Products List

Dear Customer,

Please find below the Standard Public Products List impacted by the change:

### ST COMMERCIAL PRODUCT

LD2979M30TR	LD2979M33TR	LD2980ABM30TR
LD2980ABM33TR	LD2980ABM50TR	LD2980CM18TR
LD2980CM33TR	LD2980CM50TR	LD2981CM50TR
LD2985BM18R	LD2985BM25R	LD2985BM28R
LD2985BM30R	LD2985BM33R	LD2985BM50R
LD39015M08R	LD39015M10R	LD39015M125R
LD39015M12R	LD39015M15R	LD39015M18R
LD39015M25R	LD39015M33R	LD3985M122R
LD3985M25R	LD3985M27R	LD3985M28R
LD3985M29R	LD3985M30R	LD3985M33R
LD3985M47R	LDCL015M33R	LDCL015MR
LDS3985M18R	LDS3985M25R	LDS3985M28R
LDS3985M30R	LDS3985M33R	LDS3985M50R
LK112M15TR	LK112M18TR	LK112M25TR
LK112M33TR	LK112M50TR	LK112M55TR
LK112M60TR	LK112M80TR	LK112SM18TR
LK112SM33TR	LK112SM50TR	ST715M25R
ST715M33R	ST715MR	

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